EE 435

Lecture 38

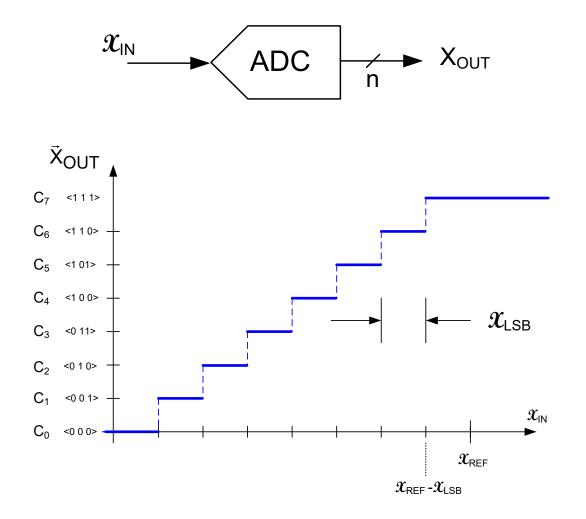
ADC Design

Analog to Digital Converters



Will now focus on design of ADCs

Analog to Digital Converters



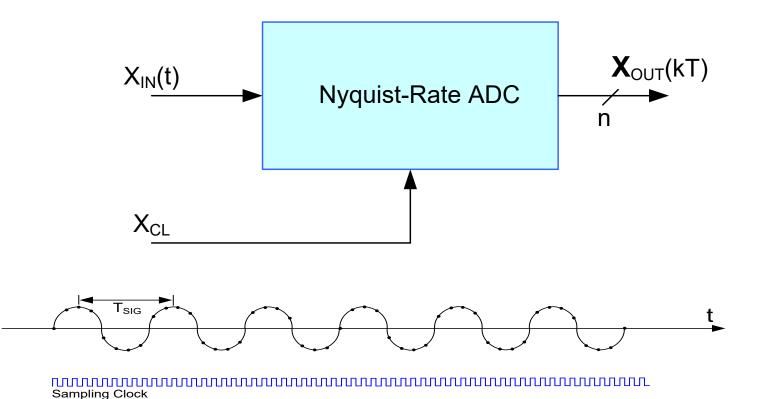
Analog to Digital Converters

The conversion from analog to digital in most ADCs is done with comparators

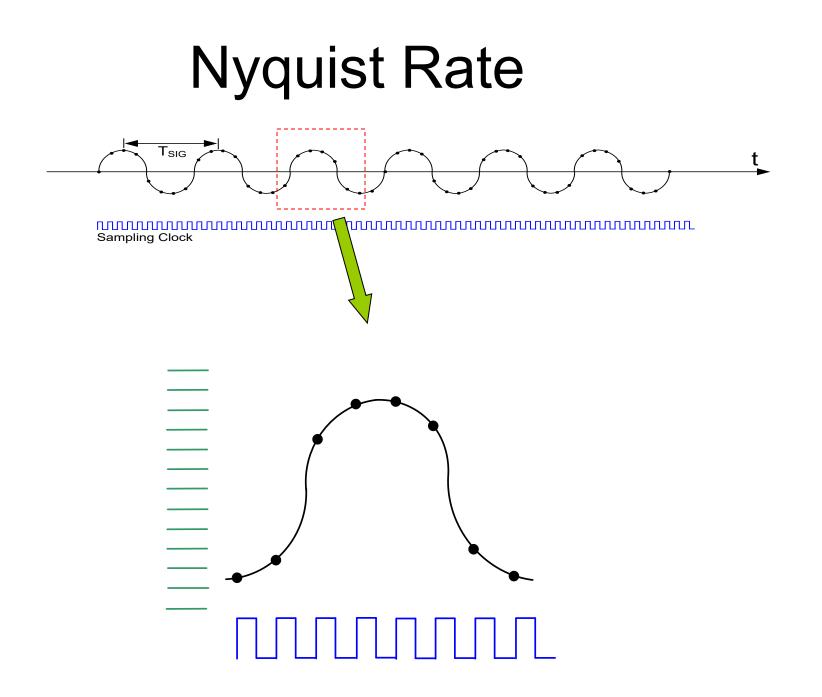


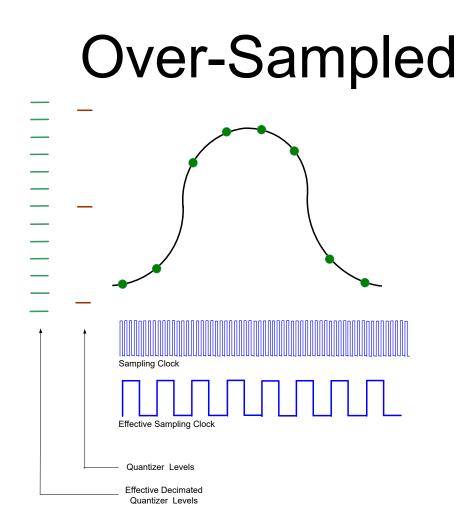
Most ADC design is primarily involved with designing comparators and embedding these into circuits that are robust to nonideal effects

Nyquist Rate



Nyquist Rate Data Converters provide one output for each period of the sampling clock

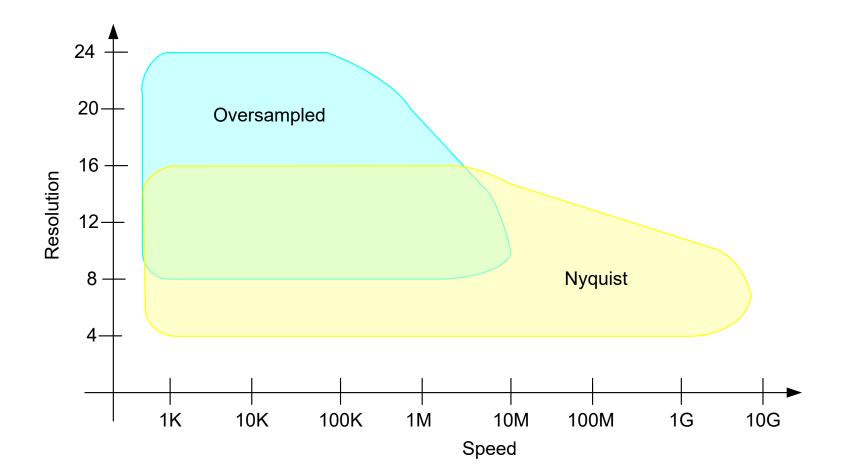




Over-Sampled Data Converters require multiple sampling clock periods for each output

Over-sampling ratios of 128:1 or 64:1 are common Dramatic reduction in quantization noise effects Limited to relatively low effective conversion rates

Data Converter Type Chart



ADC Types

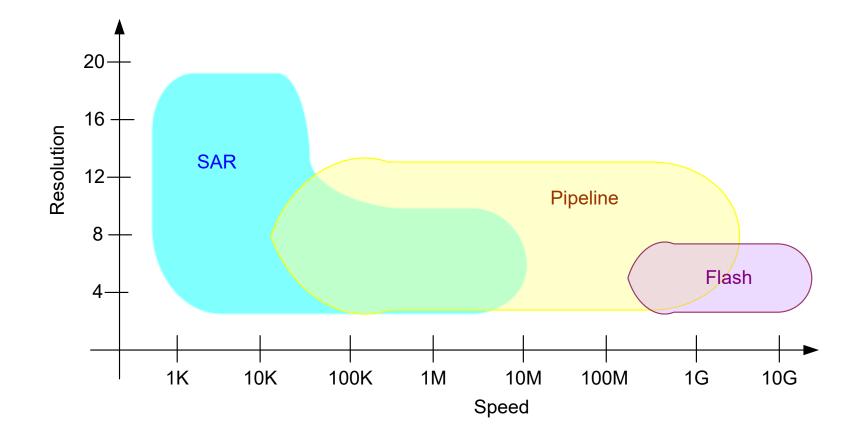
Nyquist Rate

Over-Sampled

- Flash
- Pipeline
- Two-Step Flash
- Multi-Step Flash
- Cyclic (algorithmic)
- Interpolating
- Successive Approximation
- Folded
- Dual Slope

- Single-bit
- Multi-bit
- First-order
- Higher-order
- Continuous-time

Nyqyist Rate Usage Structures



What Architectures are Actually Used

DACs Texas Instruments Mar 1, 2023

String	168
R-2R	79
Current Source	52
MDAC	23
Current Sink	17
SAR	9
Pipeline	7
Delta Sigma	4
1-Steering	3
Current Steering	2

ADCs Texas Instruments April 13 2023

SAR	728
Pipeline	294
Delta Sigma	187
Folding Interpolating	66
Delta Sigma	
Modulator	9
Two-Step	6
Flash	3
Total	1293

- These are catalog parts
- Specific details about architecture usually absent in data sheets
- Some (many) in list are slight variants and carry different part numbers
- Variety of converters used in ASIC applications will be larger

ADC Types

Nyquist Rate

- Flash
- Pipeline
- Two-Step Flash
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- Cyclic (algorithmic)
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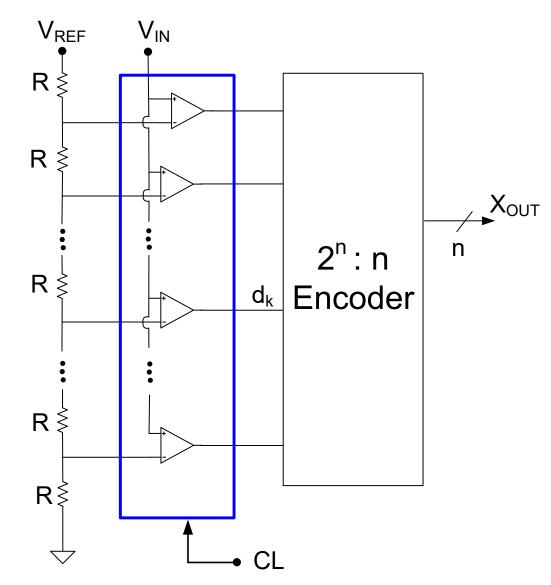
Over-Sampled

- Single-bit
- Multi-bit
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- Continuous-time

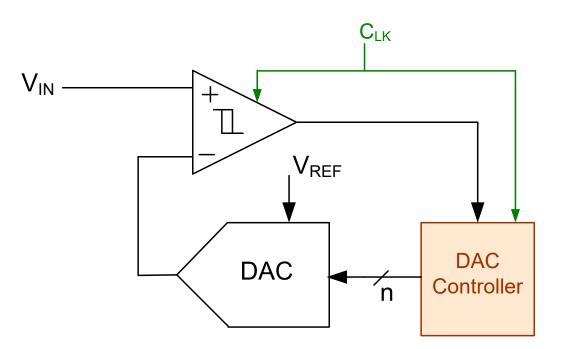
All have comparable conversion rates

Basic approach in all is very similar

Flash ADC



SAR ADC



- DAC Controller may be simply U/D counter
- Binary search controlled by Finite State Machine is faster
- SAR ADC will have no missing codes if DAC is monotone
- Not very fast but can be small

Flash ADC

Asynchronous operation (benefit or liability?)

Vulnerable to missing codes

High number of comparators needed (for large n)

R-string area requires considerable area and source of INL limitations

Offset voltage of comparators of concern

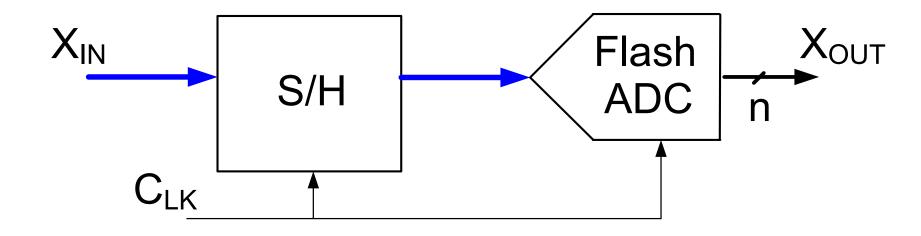
Simultaneous switching of large number of comparators can cause supply glitches Large parasitic capacitance on V_{IN} pin

Bubbles in output can occur

Metastability an issue

Power dissipation can be large

Flash ADC with Front-End S/H



Prevents input to ADC from changing during sampling (Synchronous instead of Asynchronous)

Performance of ADC can be no better than that of the S/H

Significant amount of effort and power may go into the S/H

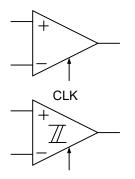
Comparators

High-Gain Saturating Amplifier

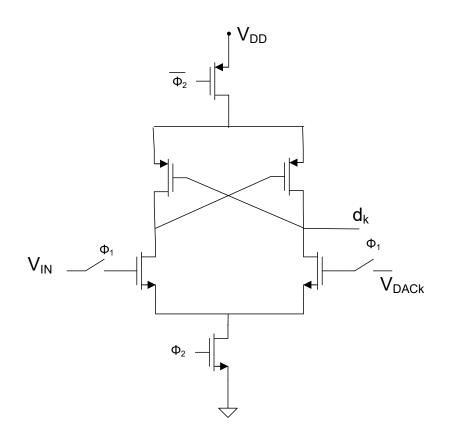
Clocked Comparator

Linear High-gain Amplifier

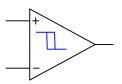
Regenerative Feedback Amplifier



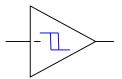
Clocked Comparator



Regenerative Comparators



Differential

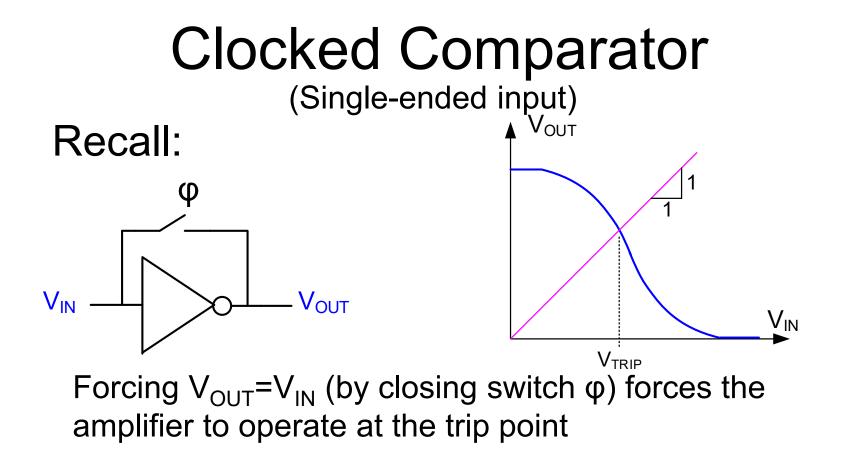


Single-Ended

Regenerative Feedback

Large offset voltage (100mV or more)

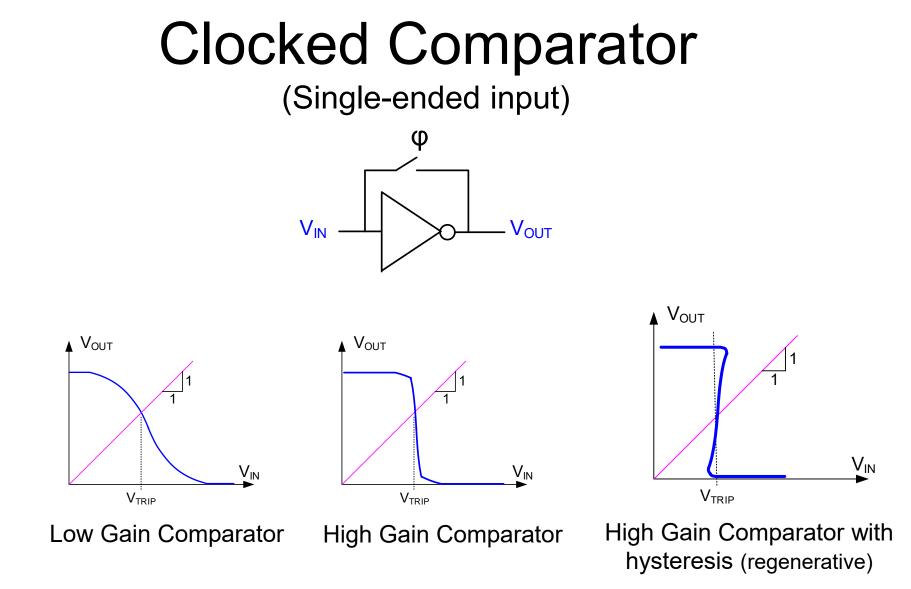
Previous-decision affects offset



Concept applicable irrespective of how large the gain of the amplifier is

But power dissipation may be high when ϕ is activated

How can this property be exploited to form clocked comparator?



If goal is to compare V_{IN} with V_{TRIP} , have clocked comparator But comparison point highly process dependent thus limiting this approach

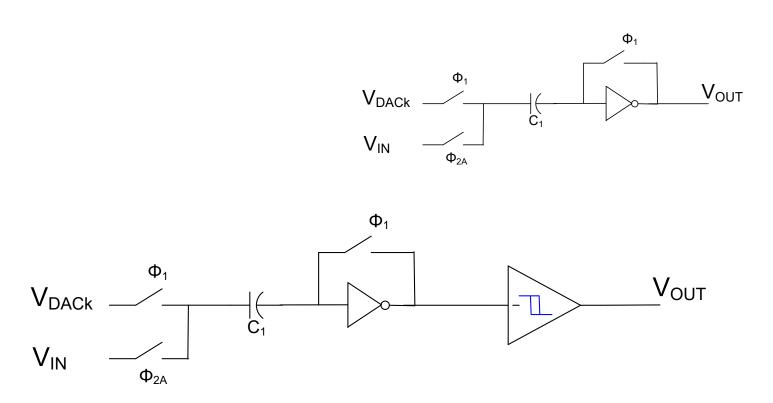
Clocked Comparator (Single-ended input) Comparison now with $V_{DACk} \bigoplus_{\Phi_1} V_{OUT}$

Amplifier may be viewed as a preamplifier with offset compensation

- Ideally removes all offset effects
- May not have a large enough gain
- Regenerative latch often used (either for gain block or following)

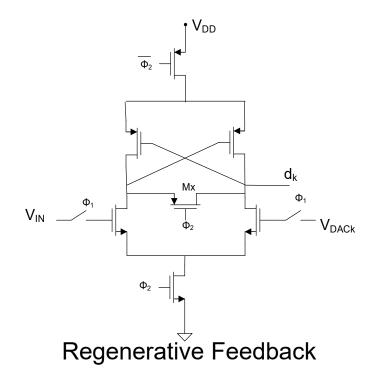
Clocked Comparator

(Single-ended input)

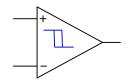


Preamplifier with offset compensation and regenerative latch Gain of preamplifier may still not be large enough Can use two pre-amp stages and/or offset compensation on latch

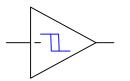
Clocked Comparator with Regenerative Feedback



Regenerative Comparators



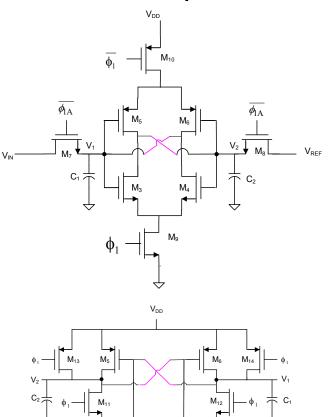
Differential



Single-Ended

- Mx used to reduce (eliminate) previous code dependence on comparator decision
- Regenerative feedback often used to force decision when differential inputs are small
- Several variants of clocked comparators are available
- Important to not have trip point dependent upon previous comparison results
- Often one or more linear gain stages precede the regenerative stage
- Power dissipation can be small in regenerative feedback comparators
- Large offset voltage (100mV or more) common for regenerative feedback comparators

Clocked Comparator with Regenerative Feedback

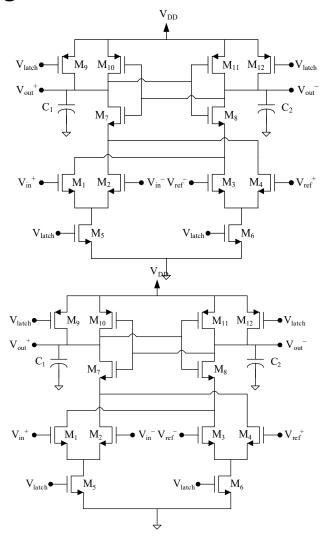


 M_3

M

+

VIN



 V_{REF} denotes V_{DACk} in these figures

 V_{REF}

 M_8

Flash ADC Summary

Flash ADC Very fast Simple structure Usually Clocked Bubble Removal Important Seldom over 6 or 7 bits of resolution

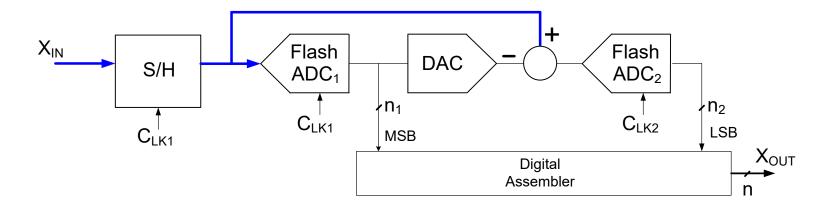
- Flash ADC has some really desirable properties (simple and fast)
- Wouldn't it be nice if we could derive most of the benefits of the FLASH ADC without the major limitations

To be practical at higher resolution, must address the major limitation of the FLASH ADC

Major Limitation of FLASH ADC at higher resolutions?

Number of comparators increases geometrically --- 2ⁿ

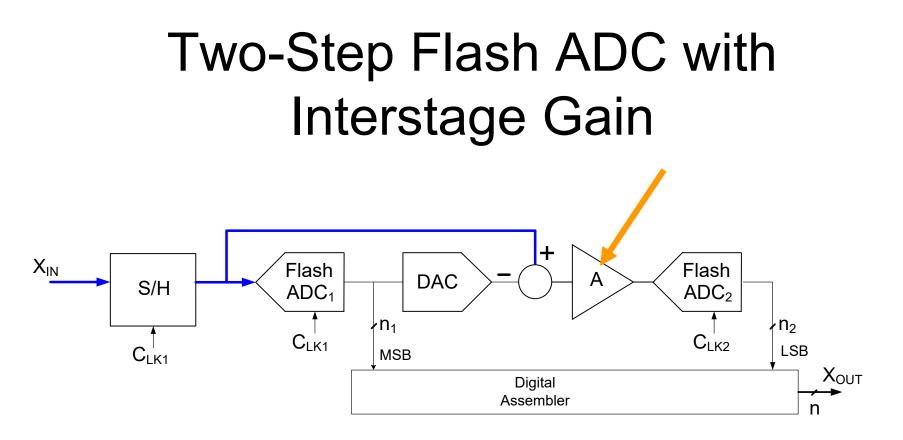
Two-Step Flash ADC



Can operate asynchronously (either after first S/H or even w/o S/H)

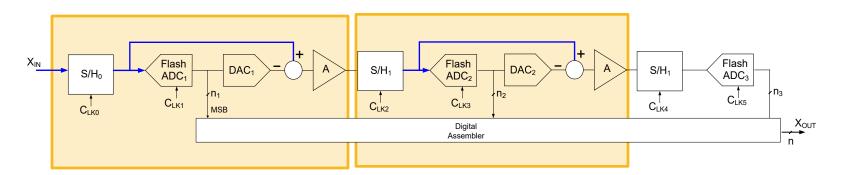
Reduces the number of comparators significantly Reduces complexity of thermometer to binary converter Residue signal at input to second Flash ADC is small Difference block is a linear module that must be accurate Have added a DAC that must have accuracy at the overall ADC resolution level

Speed of difference amplifier and DAC limit speed of ADC Sequential clocking of ADC_1 and ADC_2 limits speed of ADC



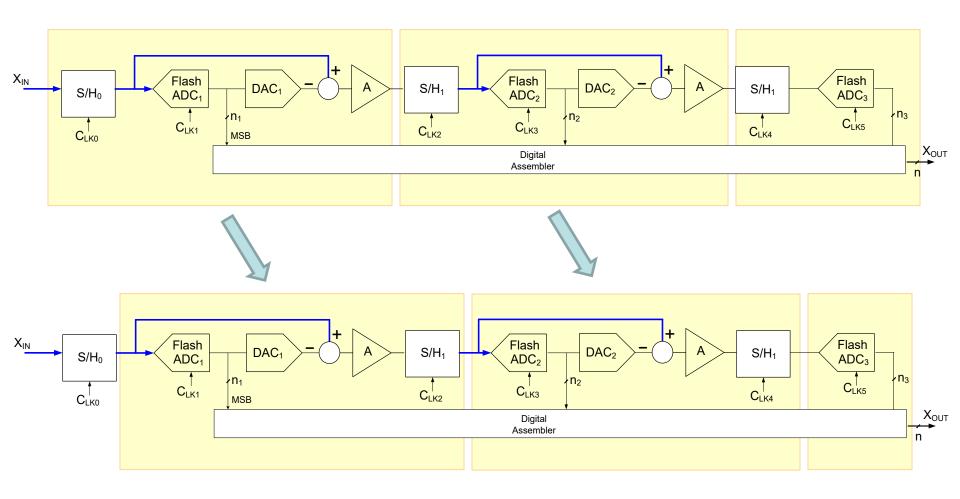
Increases level of signals into second Flash ADC (reducing offset concerns by a factor of A) Speed of A of concern Considerable power dissipation in A amplifier Complexity is increasing significantly !

Three-Step Flash ADC with Interstage Gain and S/H



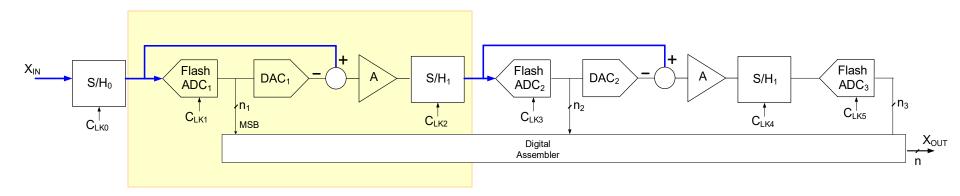
- Further reduces number of comparators needed!
- Even more complexity!
- But appears first two stages perform identical operations (if n₁=n₂)
- S/H₁ frees first stage to take another sample during second stage conversion
- S/H₂ frees second stage to take another sample during third stage conversion
- This has a pipelining capability !

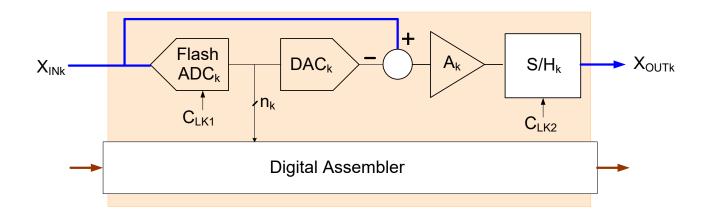
Three-Step Flash ADC with Interstage Gain and S/H



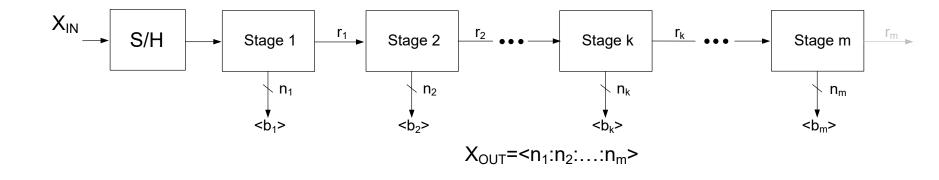
Same structure, different grouping!

Three-Step Flash ADC with Interstage Gain

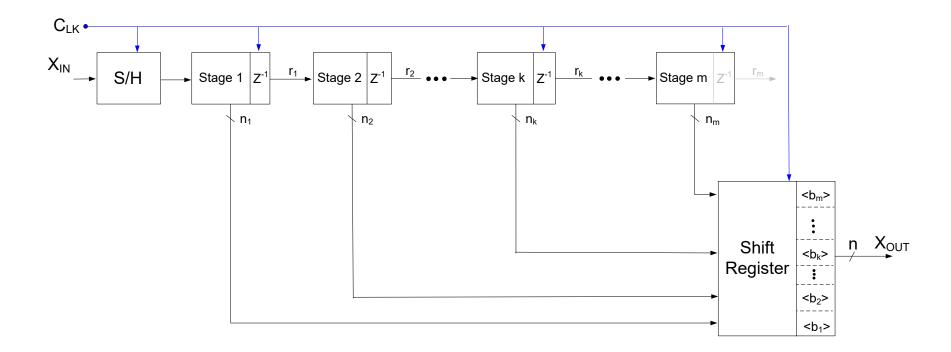


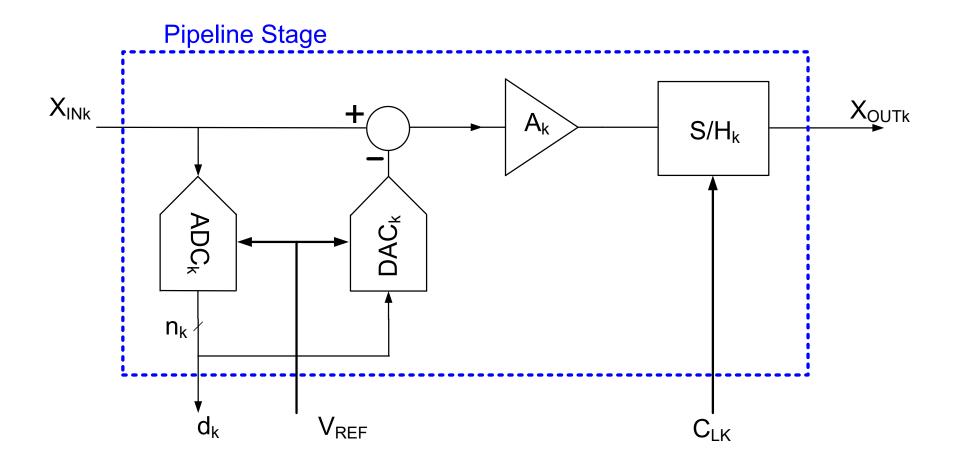


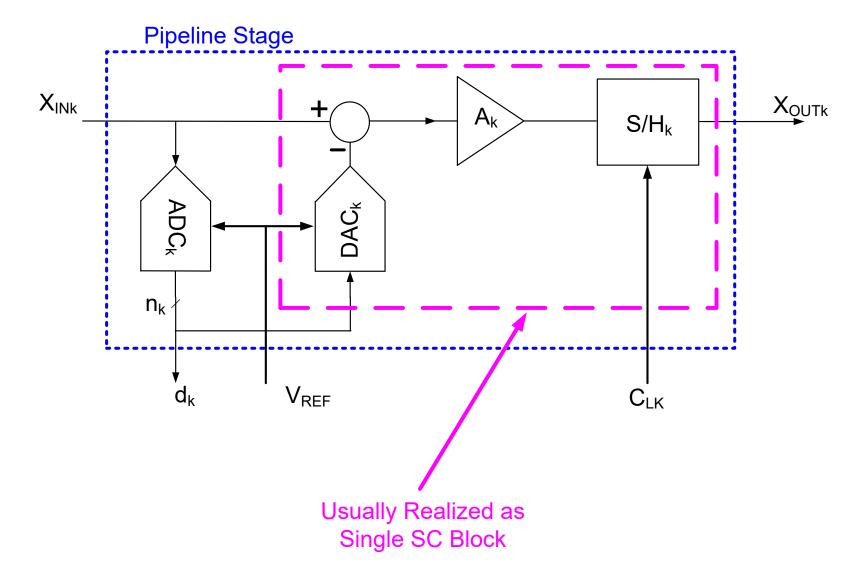
Pipelined ADC

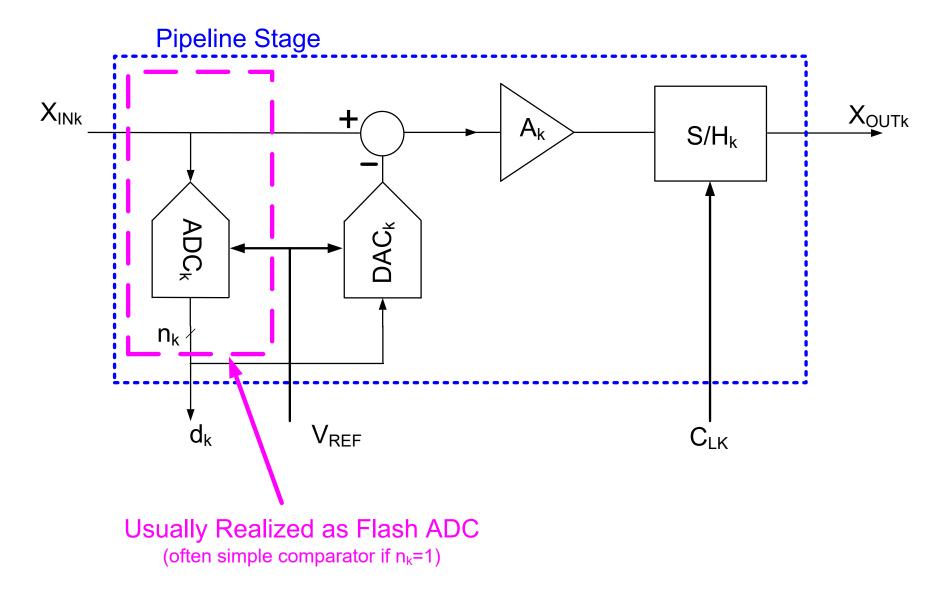


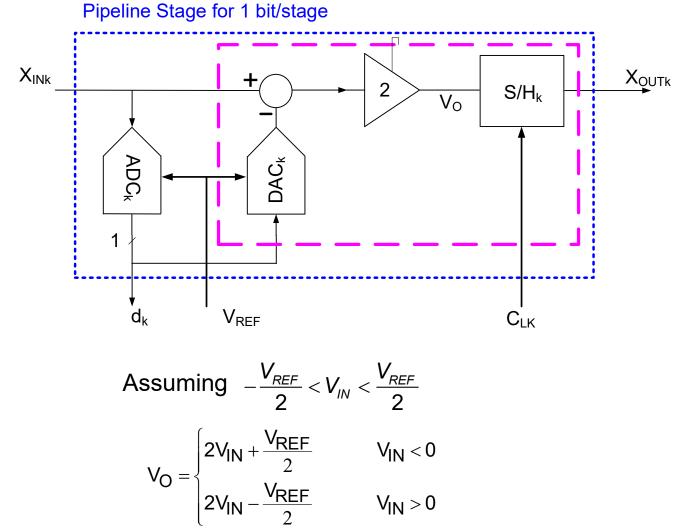
Pipelined ADC



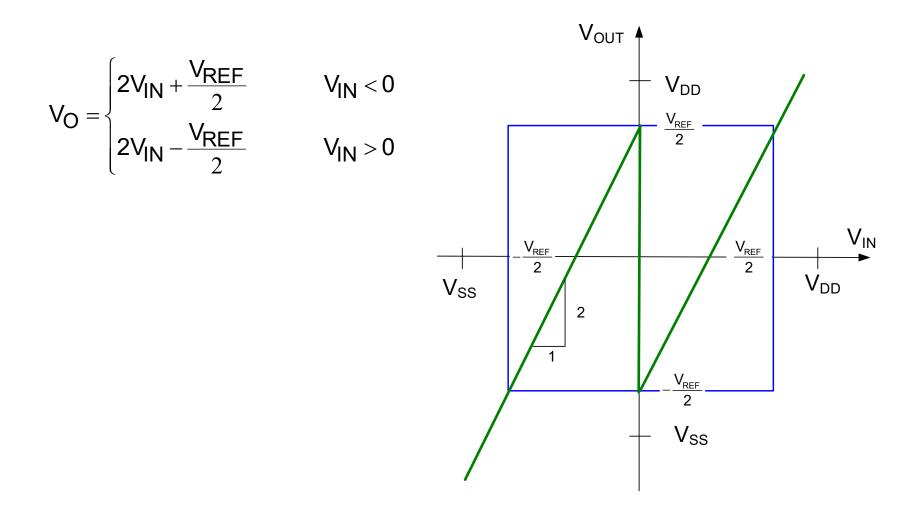


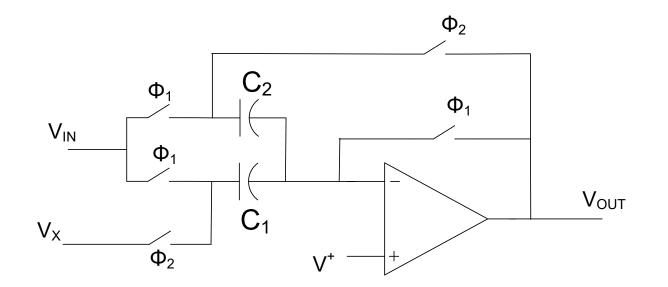


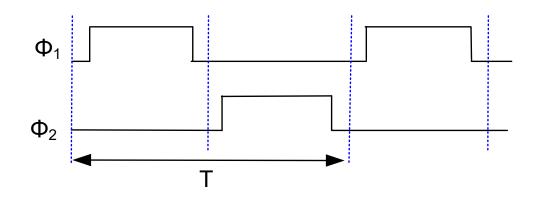


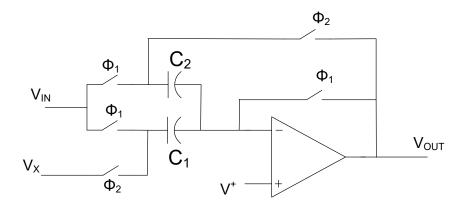


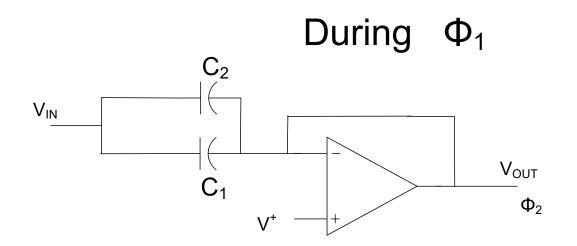
Transfer Characteristics for 1 bit/stage

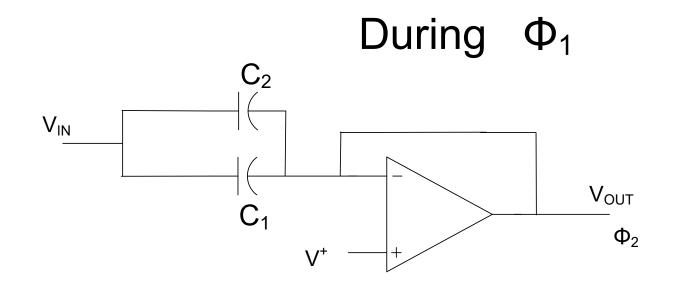




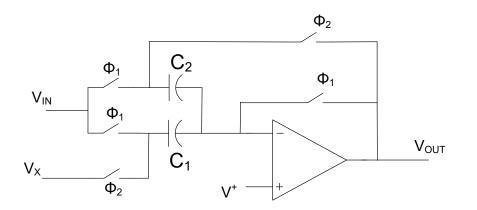




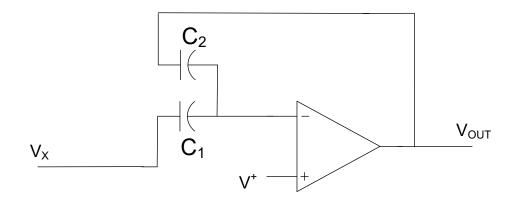


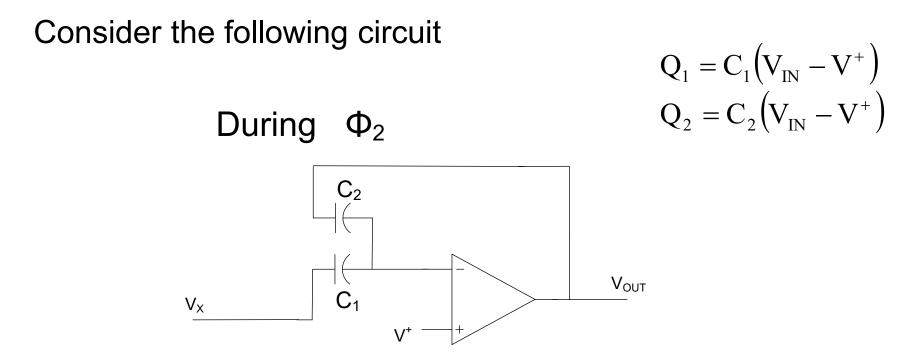


$$\begin{aligned} \mathbf{Q}_1 &= \mathbf{C}_1 \Big(\mathbf{V}_{\mathrm{IN}} - \mathbf{V}^+ \Big) \\ \mathbf{Q}_2 &= \mathbf{C}_2 \Big(\mathbf{V}_{\mathrm{IN}} - \mathbf{V}^+ \Big) \end{aligned}$$



During Φ_2



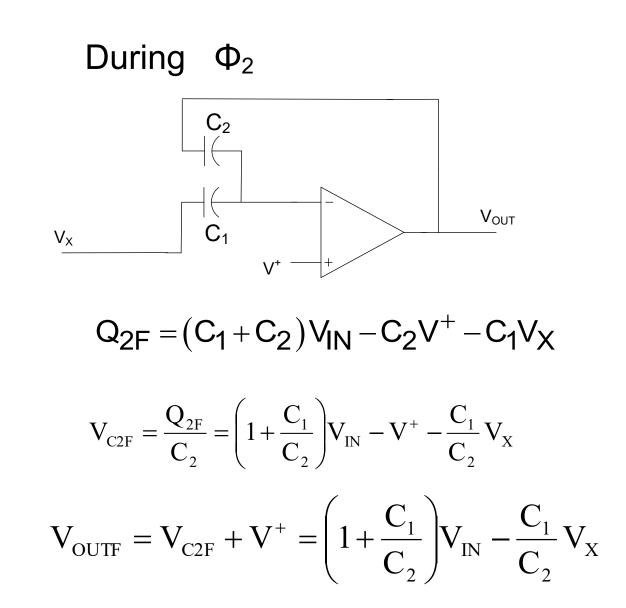


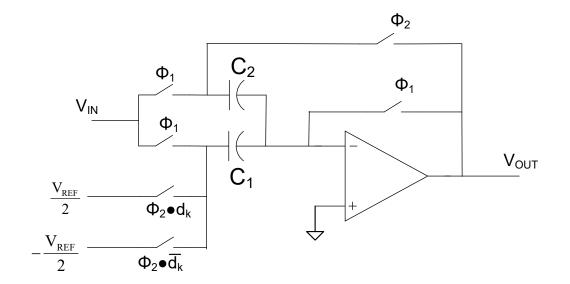
Define Q_{1T} to be the charge transferred from C_1 during phase Φ_2

$$Q_{1T} = C_1 (V_{1N} - V^+) - C_1 (V_X - V^+) = C_1 (V_{1N} - V_X)$$

Define $Q_{2\text{F}}$ to be the total charge on C_2 during phase Φ_2

$$Q_{2F} = Q_2 + Q_{1T} = C_2 (V_{1N} - V^+) + C_1 (V_{1N} - V_X) = (C_1 + C_2) V_{1N} - C_2 V^+ - C_1 V_X$$

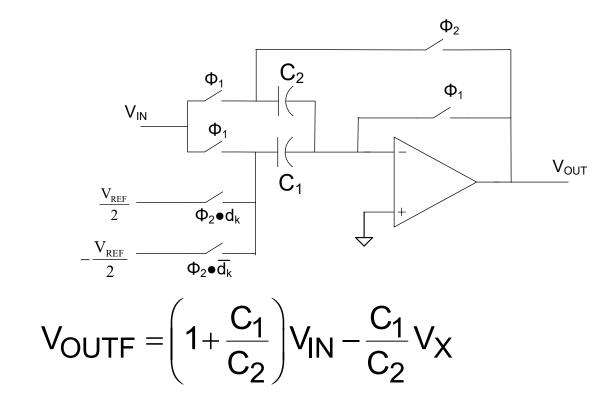




$$V_{OUTF} = \left(1 + \frac{C_1}{C_2}\right) V_{IN} - \frac{C_1}{C_2} V_X$$

If
$$C_1 = C_2 = C$$
 and $V_X = -\frac{V_{REF}}{2}$

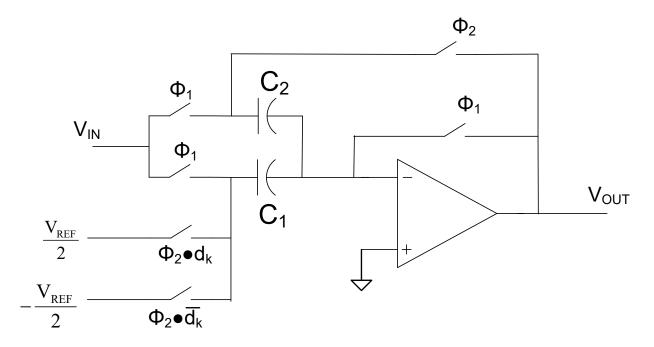
$$V_{OUTF} = 2V_{IN} + \frac{V_{REF}}{2}$$



Likewise

If
$$C_1 = C_2 = C$$
 and $V_X = \frac{V_{REF}}{2}$
 $V_{OUTF} = 2V_{IN} - \frac{V_{REF}}{2}$

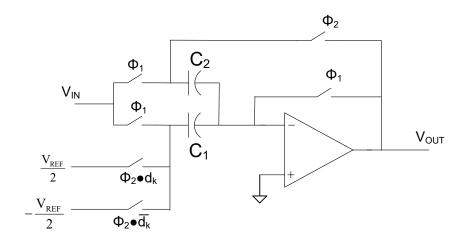
Observe

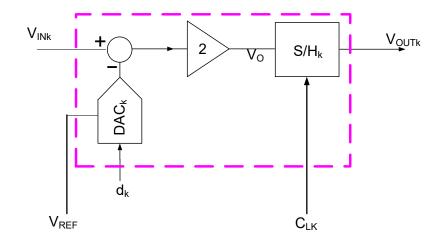


$$V_{O} = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} \\ 2V_{IN} - \frac{V_{REF}}{2} \end{cases}$$

 $V_{IN} < 0$ $V_{IN} > 0$

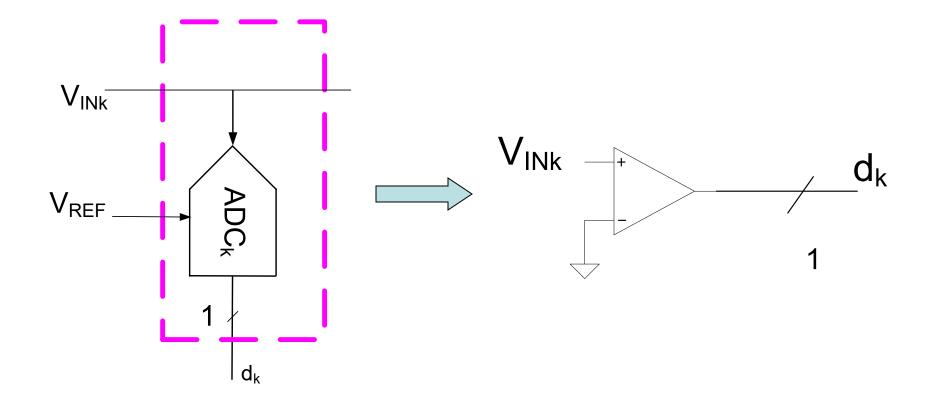
1-bit/Stage Pipeline Implementation



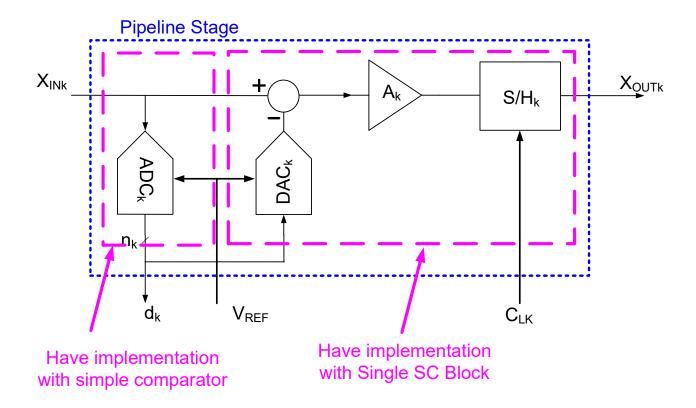


$$V_{O} = \begin{cases} 2V_{IN} + \frac{V_{REF}}{2} & V_{IN} < 0\\ \\ 2V_{IN} - \frac{V_{REF}}{2} & V_{IN} > 0 \end{cases}$$

1-bit/Stage Pipeline Implementation

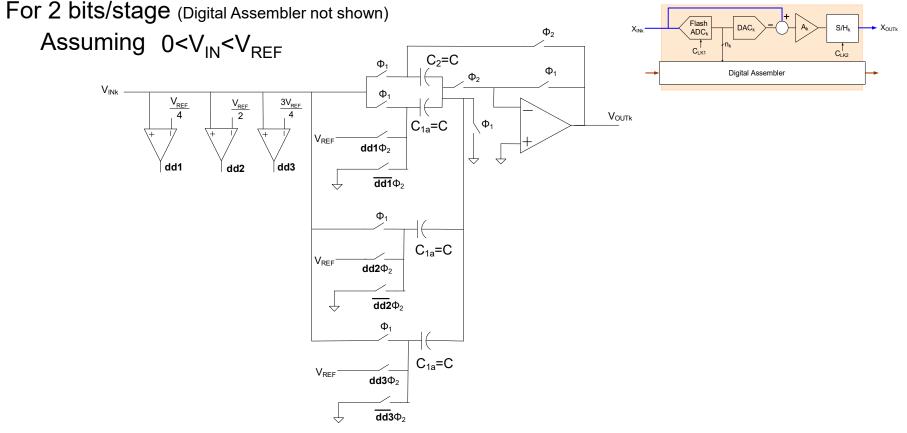


Pipelined ADC Stage k



- Have shown simple implementation with 1-bit/stage structure
- Implementations with 2-bits/stage or 3-bits/stage also straightforward

Typical SC Pipeline Stage

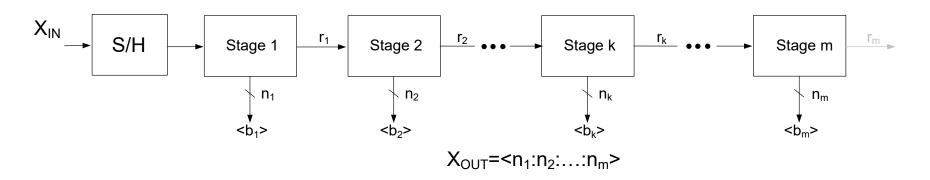


Gain =4

$$V_{\text{out}} = V_{\text{IN}} \left(1 + \frac{C_{\text{ta}} + C_{\text{tb}} + C_{\text{tc}}}{C_{\text{2}}} \right) - \left(d_{\text{dt}} \left(\frac{C_{\text{ta}}}{C_{\text{2}}} \right) + d_{\text{d2}} \left(\frac{C_{\text{tb}}}{C_{\text{2}}} \right) + d_{\text{d3}} \left(\frac{C_{\text{tb}}}{C_{\text{2}}} \right) \right) V_{\text{REF}} \implies V_{\text{OUTk}} = 4 V_{\text{INk}} - \left(d_{\text{dd}} + d_{\text{dd}} + d_{\text{dd}} \right) V_{\text{REF}}$$

- Directly use thermometer code outputs
- Can be extended to more bits/stage
- Accurate gain possible with good layout

Pipelined ADC



- Pipelined structure is widely used
- More than one bit/stage is often used
- Optimal number of bits/stage still an area of debate
- Conceptually can simply design one stage and then copy/paste to increase resolution
- Accuracy (and correspondingly power) in latter stages can be dramatically reduced
- Most power consumed in op amps
- Power dominantly allocated to S/H and MSB stages



Stay Safe and Stay Healthy !

End of Lecture 38